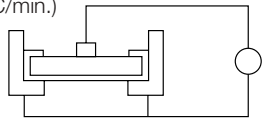


Chip Resistor Arrays



CR, CJ, CRA, CRB, CRC Series - Test Conditions

ELECTRICAL CHARACTERISTICS

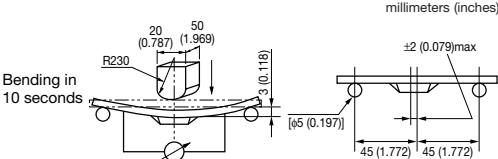
Item		Standard		Test Conditions							
		Resistor	Jumper	Resistor	Jumper						
DC Resistance		Within Initial Tolerance		Power Condition A (20°C, 65% RH)							
Temperature Characteristics		<table><tr><th>Resistance (Ω)</th><th>TCR (ppm/°C)</th></tr><tr><td>*D, F 10≤ R ≤1M</td><td>-100 to +100</td></tr><tr><td>J, CR05 = F R <10 10≤ R ≤1M 1M< R</td><td>-100 to +600 -250 to +250 -500 to +300</td></tr></table>	Resistance (Ω)	TCR (ppm/°C)	*D, F 10≤ R ≤1M	-100 to +100	J, CR05 = F R <10 10≤ R ≤1M 1M< R	-100 to +600 -250 to +250 -500 to +300		Test Temperature: 25, 125(°C) ΔR/R=R₂–R₁/R₁×1/T₂–T₁×10⁶ ΔR/R = Temp. Coefficient (ppm/°C) T₁ = 25(°C) T₂ = 125(°C) R₁ = T₁ Resistance at (Ω) R₂ = T₂ Resistance at (Ω)	
Resistance (Ω)	TCR (ppm/°C)										
*D, F 10≤ R ≤1M	-100 to +100										
J, CR05 = F R <10 10≤ R ≤1M 1M< R	-100 to +600 -250 to +250 -500 to +300										
Short-time Overload	ΔR/R	±(2.0%+0.10Ω) max. of the initial value	50mΩ max.	(1) Apply 2.0 x rated voltage for 5 sec. (2.5 x rated voltage for Arrays) (2) Wait 30 minutes (3) Measure resistance CR03 = 30V max. CR05 = 50V max CR10 = 100V max. CR21 = 200V max. CR32 = 400V max. CRA3A, CRB3A, CRC3A = 100V max.	(1) 2A for 5 sec. (CJ03 = 1A) (2) Wait 30 minutes (3) Measure resistance						
	Visual	No evidence of mechanical damage intermittent overload									
Intermittent Overload	ΔR/R	±(5%+0.1Ω) max. of the initial value	50mΩ max.	(1) Perform 10,000 voltage cycles as follows: ON (2.0 x rated voltage, 2.5 x for Arrays) 1 sec. OFF 25 sec. (2) Stabilization time 30 min. without loading (3) Measure resistance CR03 = 30V max. CR05 = 50V max. CR10 = 150V max. CR21 = 200V max. CR32 = 400V max. CRA, CRB, CRC = 100V max.	(1) Perform 10,000 current cycles as follows: ON (2A) 1 sec. OFF 25 sec. (2) Wait 30 minutes (3) Measure resistance CJ03 = 1A max.						
	Visual	No evidence of mechanical damage									
Dielectric Withstanding Voltage		No evidence of mechanical damage			Apply 500 VAC for 1 min. (CR10 300 VAC) (CR05, CRA3A, CRB3A, CRC3A 300 VAC/1 sec. CR03 50 VAC/min.)						
Insulation Resistance		• CR03, CJ03 = 10⁸Ω min. • CR05, CJ05 = 10⁸Ω min. • CR10, CJ10 = 10⁹Ω min. • CR21, CJ21 = 10¹⁰Ω min. • CR32, CJ32 = 10¹²Ω min. • CRA3A, CRB3A, CRC3A = 10⁹Ω min.			Apply 500V DC (CR05, CRA3A, CRB3A, CRC3A 100V DC CR03 50 VDC) 						

Chip Resistor Arrays



CR, CJ, CRA, CRB, CRC Series - Test Conditions

MECHANICAL CHARACTERISTICS

Item		Standard		Test Conditions	
		Resistor	Jumper	Resistor	Jumper
Terminal Strength	$\Delta R/R$	$\pm(1\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Apply the load as shown: Measure resistance during load application	
	Visual	No evidence of mechanical damage after loading		 PC Board = Glass epoxy t = 1.60 (0.063)	
Soldering Heat Resistance	$\Delta R/R$	$\pm(1\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Immerse into molten solder at $260\pm 5^{\circ}\text{C}$ for 10 ± 1 sec. Stabilize component at room temperature for 1 hr. Measure resistance.	
	Visual	No evidence of leaching			
Solderability		Coverage $\geq 95\%$ each termination end		Immerse in Rogin Flux for 2 ± 0.5 sec. and in SN62 solder at $235\pm 5^{\circ}\text{C}$ for 2 ± 0.5 sec.	
Anti-Vibration Test	$\Delta R/R$	$\pm(1\%+0.1\Omega)$ max. of the initial value	50m Ω max.	2 hrs. each in X, Y and Z axis. (TTL 6 hrs.) 10 to 55 Hz sweep in 1 min. at 1.5mm amplitude.	
	Visual	No evidence of mechanical damage			
Solvent Resistance	$\Delta R/R$	$\pm(0.5\%+0.05\Omega)$ max. of the initial value	50m Ω max.	Immerse in static state butyl acetate at 20°C to 25°C for 30 ± 5 sec. Stabilize component at room temperature for 30 min. then measure value.	
	Visual	No evidence of mechanical damage			

ENVIRONMENTAL CHARACTERISTICS

Item		Standard		Test Conditions	
		Resistor	Jumper	Resistor	Jumper
Temperature Cycle	ΔR/R	±(1%+0.05Ω) max. of the initial value	50mΩ max.	(1) Run 5 cycles as follows: -55±3°C for 30 min. 125±3°C for 30 min. Room temp. for 10-15 min. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Low Temperature Storage	ΔR/R	±(2%+0.1Ω) max. of the initial value	50mΩ max.	(1) Dwell in -55°C chamber without loading for 1000 ⁺⁴⁸ ₋₀ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
High Temperature Storage	ΔR/R	±(3%+0.1Ω) max. of the initial value	50mΩ max.	(1) Dwell in 125°C chamber without loading for 1000 ⁺⁴⁸ ₋₀ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Moisture Resistance	ΔR/R	±(3%+0.1Ω) max. of the initial value	50mΩ max.	(1) Dwell in temp.: 65°C RH90 to 95% RH chamber without loading for 1000 ⁺⁴⁸ ₋₀ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Life Test	ΔR/R	±(3%+0.1Ω) max. of the initial value	50mΩ max.	(1) Temp.: 70±3°C Voltage: (rated voltage) on 90 min. off 30 min. Duration: 1000 ⁺⁴⁸ ₋₀ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			
Loading Life in Moisture	ΔR/R	±(3%+0.1Ω) max. of the initial value	50mΩ max.	(1) Temp.: 40±2°C RH: 90-95% Voltage Cycle: on 90 min. (rated voltage) off 30 min. Duration: 1000 ⁺⁴⁸ ₋₀ hrs. (2) Stabilize component at room temperature for 1 hr. then measure value.	
	Visual	No evidence of mechanical damage			

Packaging of Chip Component



Automatic Insertion Packaging

TAPE AND REEL

REEL DIMENSIONS

millimeters (inches)

	Tape Size	A Max.	B Min.	C	D Min.	N Min.	W	T Max.
	8mm	178 (7) 260 (10)	1.50 (0.059)	13.0±0.50 (0.512±0.020)	20.2 (0.795)	50 (1.969)	10.0±1.50 (0.394±0.059)	2.50 (0.098)

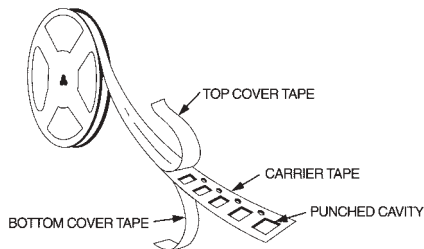
Metric dimensions will govern.
English measurements rounded and for reference only.

millimeters (inches)

PUNCHED TAPE CONFIGURATION 8MM TAPE ONLY						
Tape Size	D ₀	E	P ₀	P ₂	W	F
8mm	1.50 ^{+0.10} / _{-0.00} (0.059 ^{+0.004} / _{-0.000})	1.75±0.10 (0.069±0.004)	4.0±0.10 (0.157±0.004)	2.00±0.05 (0.079±0.002)	8.00±0.20 (0.135±0.008)	3.50±0.05 (0.138±0.002)

PUNCHED CARRIER				
Style	P ₁	A ₀	B ₀	T max.
CR/CJ03 CR/CJ05	2.00±0.10 (0.079±0.004)	0.65±0.10 (0.026±0.004)	1.15±0.10 (0.045±0.004)	0.60 (0.024)
CR/CJ/FR10	4.00±0.10 (0.157±0.004) or 2.00±0.10 (0.079±0.004)	1.10±0.20 (0.043±0.008)	1.90±0.20 (0.075±0.008)	1.10 (0.043)
CR/CJ/FR21	4.00±0.10 (0.157±0.004)	1.65±0.20 (0.065±0.008)	2.40±0.20 (0.094±0.008)	
CR/CJ/FR32		2.00±0.20 (0.079±0.008)	3.60±0.20 (0.142±0.008)	
CRB1A		1.90±0.20 (0.075±0.008)	1.90±0.20 (0.075±0.008)	
CRA3A CRB3A CRC3A		2.00±0.20 (0.079±0.008)	3.60±0.20 (0.142±0.008)	
CRB2A	2.00±0.10 (0.079±0.004)	1.25±0.20 (0.049±0.008)	2.50±0.20 (0.098±0.008)	

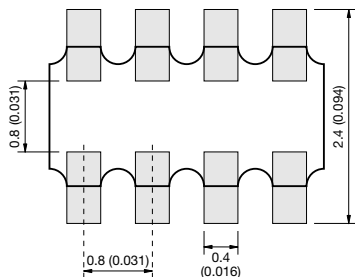
PUNCHED CARRIER



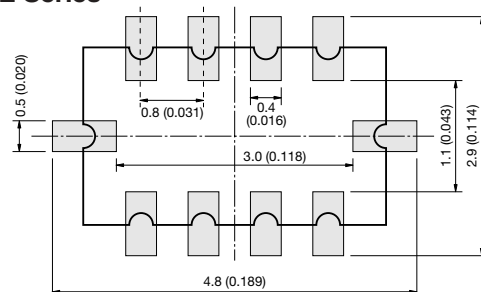
RECOMMENDED LAND PATTERNS IS REFERRED THE FOLLOWING FOR EXAMPLE

millimeters (inches)

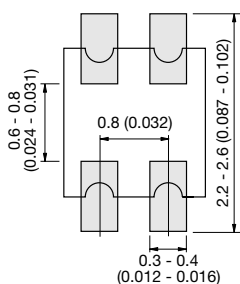
CRA3A4E Series



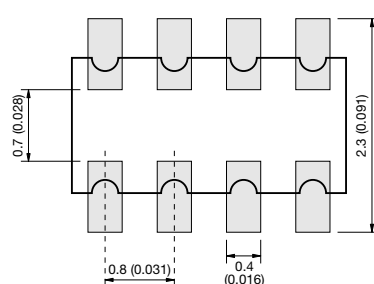
RNA4A8E Series



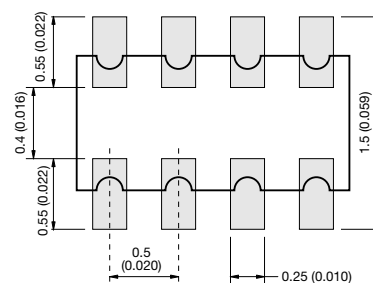
CRB1A2E Series



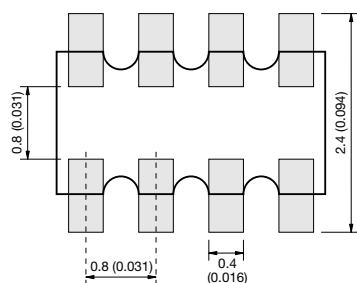
CRB3A4E Series



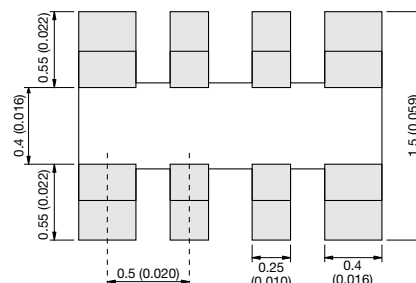
CRB2A4E Series



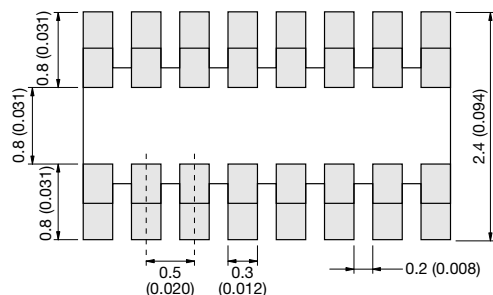
CRC3A4E Series



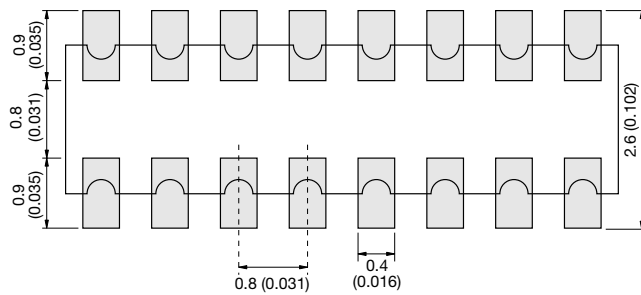
CRC2A4E Series



CRC4A8E Series



CRB6A8E Series



SAMPLE KIT PART NUMBERS

Part Number	Description
CRJ-E6-Kit	Combination 0603, 0805, 1206, 5% parts 21 values per case size 100 pcs. per value (approx.)
CR05-E12-Kit	0402, 5% parts 63 values 100 pcs. per value
CR10J-E12-Kit	0603, 5% parts 63 values 100 pcs. per value (approx.)
CR21J-E12-Kit	0805, 5% parts 63 values 100 pcs. per value (approx.)
CR32J-E12-Kit	1206, 5% parts 63 values 100 pcs. per value (approx.)
CR05F-E24-Kit	0402, 1% parts 63 values 100 pcs. per value
CR10F-E24-Kit	0603, 1% parts 63 values 100 pcs. per value
CR-ARRAY-E6-Kit	Arrays, Various styles, CRA, CRB, CRC, RNA, 5% 13 values per style (approx.) 20 pcs. per value